

The conference is devoted to the memory  
of professor Leonid S. Smirnov

**IV<sup>th</sup> Russian Conference**  
**PHYSICAL AND PHYSICO-CHEMICAL BASES OF ION**  
**IMPLANTATION**  
(with foreign scientists participation)

and International Youth Conference  
**RADIATION EFFECTS AND PROCESSES IN INORGANIC**  
**MATERIALS**

23-26 October, 2012, Novosibirsk

# **PROGRAMME**

**Novosibirsk-2012**

# Small House of Scientists

**MONDAY, 22 OCTOBER**

**15<sup>00</sup>-18<sup>00</sup> Conferees registration**

**TUESDAY, 23 OCTOBER**

**Session 1** Chairman – **Alexander L. Aseev**

10<sup>00</sup> – 10<sup>15</sup> Opening ceremony. Introductory speech by **Alexander L. Aseev**, ISP SB RAS Director, SB RAS Chairman.

10<sup>15</sup> – 10<sup>45</sup> **V.N.Mordkovich**. Reactions assisted by own dot defects in radiated semiconductors (*invited report*)  
*Institute of the Problems of Microelectronics Technology and Ultra-Pure Materials, RAS, Chernogolovka.*

10<sup>45</sup> – 11<sup>15</sup> **A.V.Dvurechenskii**. Ion-induced molecular-beam epitaxy. Impulse annealing of nanostructures (*invited report*).  
*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*

11<sup>15</sup> – 11<sup>45</sup> **A.L.Aseev, A.V.Latyshev**. Electron and ion lithography: nanostructuring (*invited report*).  
*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*

**COFFEE BREAK - 15 min.**

**Session 2.** Chairman - **V.N.Mordkovich**

12<sup>00</sup> – 12<sup>30</sup> **R.M.Bayazitov**. Fast thermal processings in silicon-based microelectronics (*invited report*)  
*E.K.Zavoisky Kazan Physico-Technical institute of Kaz SC RAS, Kazan.*

12<sup>30</sup> – 12<sup>45</sup> **P.P.Trohimchuk.** The problem in the ratio of ionization and thermal mechanisms under laser annealing and laser doping  
*Lesya Ukrainka Volynsk National University, Lutsk, Ukraine.*

**Lunch (12<sup>45</sup>-14<sup>00</sup>)**

14<sup>00</sup> – 15<sup>30</sup> **Poster session (reports C1-1 – C1-29).**

**Session 3. Chairman – D.I.Tetelbaum.**

15<sup>30</sup> – 16<sup>00</sup> **V.V.Kozlovsky.** Semiconductors modification by proton beams (*invited report*).  
*St.-Petersburg State Polytechnical University, St.-P.*

16<sup>00</sup> – 16<sup>30</sup> **S.Rubanov<sup>1</sup>, B.A.Fairchild<sup>2</sup>, P.Olivero<sup>3</sup>, S.Prawer<sup>2</sup>.** Focused ion beam engineering of nanostructures in diamond (*invited report*)

<sup>1</sup>*Bio21 Institute, the University of Melbourne, Victoria, Australia*

<sup>2</sup>*School of Physics, the University of Melbourne, Victoria, Australia*

<sup>3</sup>*Physics Department, University of Torino, Italy*

16<sup>30</sup> - 16<sup>45</sup> **E.C.Demidov, V.V.Podolsky, V.P. Lesnikov, V.V.Karxzanov, V.V.Sdobnyakov, E.D.Pavlova, A.A.Tronov.** Ion-beam and laser synthesis of new silicon-based magnetic materials.

*N.I.Lobachevsky Nizhegorod State University, Nizhny Novgorod.*

16<sup>45</sup> – 17<sup>00</sup> **V.Yu.Petukhov, G.G.Gumarov, A.V.Alekseev, D.A.Konovalov.** Investigation of magnetic anisotropy of iron silicide thin films, ion-synthesized in magnetic and mechanical fields.

*E.K.Zavoisky Kazan Physico-Technical Institute of Kaz SC, RAS, Kazan.*

17<sup>00</sup> – 17<sup>15</sup> **I.V.Matyshkin<sup>1</sup>, S.V.Korobov<sup>1</sup>, N.A.Zaitsev<sup>1</sup>, I.A.Khomyakov<sup>1</sup>, S.N.Orlov<sup>1</sup>, A.N.Mikhailov<sup>2</sup>, D.V.Guseinov<sup>2</sup>.** Cell-automat approach to defect formation simulation under ion implantation.

<sup>1</sup>*OJSC «RI of Molecular electronics», Moscow, Zelenograd.*

<sup>2</sup>*N.I.Lobachevsky Physico-Technical Institute of NNSU, Nizhny Novgorod.*

**Coffee break - 15 min.**

## Session 4.

Chairman – R.M.Bayazitov

17<sup>30</sup> – 18<sup>00</sup> **N.G.Kolin**<sup>1</sup>, L.S.Smirnov<sup>2</sup>. Nuclear semiconductor doping. Current state and perspectives (**invited report**).

<sup>1</sup>Affiliated Branch of FSUE L.Ya.Karpov RPCI'.

<sup>2</sup>A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.

18<sup>00</sup> – 18<sup>30</sup> **V.A.Bykov**, K.Yu.Borisov, A.V.Bykov, V.V.Kotov, V.V.Polyakov. Cluster technological lines of micro- and nanoelectronics using the systems of multi-beam maskless lithography (**invited report**).

Group of "NT-MDT" enterprises, Moscow.

18<sup>30</sup> – 19<sup>00</sup> **A.F.Vyatkin**. Formation of super-narrow p-n junctions in silicon by ion implantation (**invited report**)

Institute of the Problems of Microelectronics Technology and Ultra-Pure Materials, RAS, Chernogolovka.

19<sup>15</sup> Buffet table.

**Session 5.**

**Chairman – A.F.Vyatkin**

- 09<sup>00</sup> - 09<sup>30</sup> **P.A.Karasev, A.I.Titov.** Change of GaN properties under accelerated ion radiation (*invited report*)  
*St.-Petersburg State Polytechnical University, St.-P.*
- 09<sup>30</sup> – 10<sup>00</sup> **A.V.Voitsekhovsky<sup>1</sup>, N.H.Talipov<sup>2</sup>.** Ion implantation in CMT (*invited report*)  
<sup>1</sup>*National Research Tomsk State University, Tomsk.*  
<sup>2</sup>*Peter-the Great Military Academy of RST, Moscow.*
- 10<sup>00</sup> – 10<sup>15</sup> **N.A.Dobychin, V.V.Karzanov, E.V.Semenova.** Ion implantation-induced defects in silicon nitride.  
*N.I.Lobachevsky Nizhegorod State University, Nizhny Novgorod.*
- 10<sup>15</sup> – 10<sup>30</sup> **O.V.Naumova, B.I. Fomin, M.A. Ilnitsky, V.P. Popov.** Influence of ion implantation on charge accumulation in Si/SiO<sub>2</sub> systems of SOI structures under ionizing radiation.  
*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*
- 10<sup>30</sup> – 10<sup>45</sup> **O.A.Podsvirov<sup>1</sup>, P.A.Karasev<sup>1</sup>, A.Ya.Vinogradov<sup>2</sup>, V.S.Belyakov<sup>1</sup>, A.V.Arhipov<sup>1</sup>, K.V.Karabeshkin<sup>1</sup>, N.N.Karasev<sup>3</sup>, E.N.Shubina<sup>1</sup>, A.I.Tumoev<sup>1</sup>.** Effect of ion bombardment for  $\alpha$ -C:H film properties.  
<sup>1</sup>*St.-Petersburg State Polytechnical University, St.-Petersburg.*  
<sup>2</sup>*A.F.Ioffe Physico-Technical Institute, St.-Petersburg.*  
<sup>3</sup>*St.-Petersburg State University of Information Technologies, Mechanics and Optics, St.-Petersburg.*

**Coffee break - 15 min.**

**Session 6**

**Chairman – F.F.Komarov**

- 11<sup>00</sup> – 11<sup>15</sup> **I.E.Tyschenko.** Radiation-resistant SOI structures with ion-modified buried insulator.  
*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*

- 11<sup>15</sup> – 11<sup>30</sup> **N.A.Dobychin**, V.V.Karzanov. Photoluminescence of silicon-enriched silicon nitride.  
*N.I.Lobachevsky Nizhegorod State university, Nizhny Novgorod.*
- 11<sup>30</sup> – 11<sup>45</sup> **A.A.Liamkina**, S.P.Moshchenko, V.G.Kesler. Plasmon resonance frequency control in indium nanodrops under oxygen ion oxidation in Townsend charge plasma.  
*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*
- 11<sup>45</sup> – 12<sup>00</sup> **Zh.V. Smagina**, A.V. Dvurechenskii, P.L. Novikov, A.V. Nenashev, N.P. Stepina, S.A. Rudin. Epitaxial growth of Ge nanocrystals on patterning Si surface with ion irradiation.  
*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*
- 12<sup>00</sup> – 12<sup>15</sup> **S.V.Sitnikov**<sup>1</sup>, S.S.Kosolobov<sup>1,2</sup>, A.V.Latyshev<sup>1,2</sup>. Kinetics of 3D submicron structures relaxation on the Si(111) atomic-smooth surface.  
<sup>1</sup>*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*  
<sup>2</sup>*Novosibirsk State University, Novosibirsk.*
- 12<sup>15</sup> – 12<sup>30</sup> **I.K.Beysembetov**, **N.B.Beysekhanov**, **S.K.Zharikov**, **B.K.Kenzhaliev**, **K.N.Nusupov** **T.K.Ahmetov**. Thin silicon carbide films synthesis.  
*Kazakhstan-British Technical University, Kazakhstan*
- 12<sup>30</sup> – 12<sup>45</sup> **I.R.Vakhitov**<sup>1,2</sup>, **A.A.Achkeev**<sup>1</sup>, **V.F.Valeev**<sup>2</sup>, **E.N.Dulov**<sup>1</sup>, **I.A.Faizrakhmanov**<sup>2</sup>, **L.R.Tagirov**<sup>1</sup>, **R.I.Haibullin**<sup>1,2</sup>, **M.Dobel**<sup>3</sup>. Influence of iron ions implantation regimes and subsequent thermal annealing on rutile magnetic phase composition (TiO<sub>2</sub>).  
<sup>1</sup>*Kazan Federal University, Kazan.*  
<sup>2</sup>*Kazan Physico-Technical Institute, Kazan.*  
<sup>3</sup>*Swiss Higher Technical School, Zurich.*

**Lunch (12<sup>45</sup>-14<sup>00</sup>)**

- 14<sup>00</sup> – 15<sup>30</sup> **Poster session (report C2-1 – C2-19).**

## Session 7

Chairman – A.V.Latyshev

15<sup>30</sup> - 16<sup>00</sup> **D.I.Tetelbaum, A.N.Mikhailov.** Secondary defect formation in silicon under ion radiation (**invited report**).

*Research Physico-Technical Institute of N.I.Lobachevsky Nizhegorod State University, Nizhny Novgorod.*

16<sup>00</sup> – 16<sup>30</sup> **L.I.Fedina.** Topological {113}-defects in Si as a result of own interstitial atoms and vacancies clusterization (**invited report**).

*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*

16<sup>30</sup> – 17<sup>00</sup> **N.Cherkashin, S.Reboh, A.Lubk, P.Pochet, A.Claverie and M.J.Hýtch.** Direct mapping of strain depth distributions with a nanometer spatial resolution in ion implanted Si using Dark-Field Electron Holography (**invited report**).

<sup>1</sup> *CEMES, Université de Toulouse, Toulouse, France*

<sup>2</sup> *CEA UJF, INAC, Lab Simulat Atomist (L\_ Sim), Grenoble, France*

17<sup>00</sup> – 17<sup>15</sup> **K.V.Feklistov, L.I.Fedina, A.G.Cherkov.** Ordering boron precipitants ensemble as a layered distribution: considering the influence of implantation defects on the ripening of the Ostwald ensemble.

*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*

**Coffee break — 15 min.**

## Session 8

Chairman – V.P.Popov.

17<sup>30</sup> – 18<sup>00</sup> **R.I.Khaibullin<sup>1,2</sup>, V.I.Nuzhdin<sup>1</sup>, O.N.Lopatin<sup>2</sup>, A.G.Nikolaev<sup>2</sup>.** Hemmological aspects of ion implantation into minerals and their synthetic analogs (**invited report**).

<sup>1</sup> *E.K.Zavoisky Physico-Technical Institute, Kaz SC RAS, Kazan.*

<sup>2</sup> *Kazan (Privolzhsk) Federal University, Kazan.*

18<sup>00</sup> – 18<sup>30</sup> **V.N.Brudny.** Evolution of non-metallic materials electron subsystem affected by hard radiation : electron properties of radiated semiconductors (**invited report**).

*National Research Tomsk State University, Tomsk.*

18<sup>30</sup> – 18<sup>45</sup> **V.V.Hvostov, K.F.Minnebaev, V.E.Yurasova.** Energy distribution of secondary particles under graphite nanocrystallites ion radiation.  
*M.V.Lomonosov MSU, Physiacl Faculty, Moscow.*

18<sup>45</sup> – 19<sup>00</sup> **D.A.Kartashov.** Methods of numerical evaluation of *p-n* junctions depth produced by ion implantation based on the data of relative two-wave x-ray reflectometry.  
*OJSC "RI of Molecular Electronics", Moscow, Zelenograd.*

## Thursday, 25 October

### Session 9

Chairman – R.I.Haibullin.

09<sup>00</sup> – 09<sup>30</sup> **N.A.Sobolev.** Engineering of structural defects and luminescent centres in Si light diodes implantation technology (*invited report*)  
*A.F.Ioffe Physico-Technical Institute, St.-Petersburg.*

09<sup>30</sup> – 10<sup>00</sup> **K.Nordlund, R.Wei, E.Holmström, F.Djurabekova, and A.Kuronen.** Molecular dynamics simulations of the primary state of damage in irradiated Si and GaN nanowires (*invited report*)  
*Department of Physics University of Helsinki, Finland*

10<sup>00</sup> – 10<sup>15</sup> **I.V.Antonova<sup>1</sup>, V.A.Skuratov<sup>2</sup>, I.Balberg<sup>3</sup>.** Ge nanocrystals formation in SiO<sub>2</sub> и Al<sub>2</sub>O<sub>3</sub> with high-energy ions.  
<sup>1</sup>*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*  
<sup>2</sup>*United Institute of Nuclear research, Dubna.*  
<sup>3</sup>*The Racah Institute of Physics, Hebrew University, Jerusalem, Israel*

10<sup>15</sup> – 10<sup>30</sup> **S.E.Demyanov, E.Yu.Kanyukov.** Ion-track technology to create nanostructured sensors of magnetic field.  
*SPC of the Belarus NAS on Material Science, Minsk.*

10<sup>30</sup> - 10<sup>45</sup> **G.A.Kachurin<sup>1</sup>, S.G.Cherkova<sup>1,2</sup>, V.A.Volodin<sup>1,2</sup>, A.G.Cherkov<sup>1,2</sup>, D.V.Marin<sup>1,2</sup>, G.N.Kamaev<sup>1,2</sup>, A.H.Antonenko<sup>1,2</sup>, V.A.Skuratov<sup>3</sup>.** Light-radiating nanostructures formation by fast heavy ions implantation into alternating Si/SiO<sub>2</sub> nanolayers.  
<sup>1</sup>*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*  
<sup>2</sup>*Novosibirsk State University, Novosibirsk.*  
<sup>3</sup>*United Institute of Nuclear Research, Dubna.*



- 10<sup>45</sup> - 11<sup>00</sup> **A.N.Mikhailov<sup>1</sup>**, A.I.Belov<sup>1</sup>, A.O.Timofeeva<sup>1</sup>, V.K.Vasilyev<sup>1</sup>, I.Yu.Zhavoronkov<sup>1</sup>, A.V.Barsukov<sup>1</sup>, D.S.Korolev<sup>1</sup>, D.I.Tetelbaum<sup>1</sup>, V.I.Sakharov<sup>2</sup>, I.T.Serenkov<sup>2</sup>, E.I.Shek<sup>2</sup>, N.A.Sobolev<sup>2</sup>. Ion-beam modification of silicon-based nanostructures, emitting light at wavelength 1.5 mcm.  
<sup>1</sup>Research Physico-Technical Institute of N.I.Lobachevsky, Nizhny Novgorod.  
<sup>2</sup> A.F.Ioffe Physico-Technical Institute, St.-Petersburg.

## Coffee break - 15 min.

### Session 10.

Chairman – V.V.Kozlovsky.

- 11<sup>15</sup> – 11<sup>45</sup> **N.N.Gerasimenko**. Ion synthesis of silicon-based nanostructures (*invited report*).  
*National Research University «MIET», Moscow, Zelenograd.*
- 11<sup>45</sup> – 12<sup>15</sup> **F.F.Komarov**. Ion synthesis of narrow-band A<sub>3</sub>B<sub>5</sub> semiconductor nanocrystals in silicon and silicon dioxide (*invited report*).  
*A.N.Sevchenko Institute of Applied Physical Problems of BSU, Minsk.*
- 12<sup>15</sup> – 12<sup>45</sup> **V.P.Popov<sup>1</sup>**, L.N.Safronov<sup>1</sup>, V.A.Antonov<sup>1</sup>, A.K.Gutakovsky<sup>1</sup>, V.I.Obodnikov<sup>1</sup>, S.N.Podlesny<sup>1</sup>, I.A.Kartashev<sup>1</sup>, A.V.Shishaev<sup>1</sup>, I.I.Ryabtsev<sup>1</sup>, I.N.Kupriyanov<sup>2</sup>, A.A.Kalinin<sup>2</sup>, Yu.N.Palyanov<sup>2</sup>, S.Rubanov<sup>3</sup>. Diamond structures for optoelectronics and quantum computer programming: ion implantation and annealing under pressure (*invited report*)  
<sup>1</sup>A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.  
<sup>2</sup>V.S.Sobolev Institute of Geology and Mineralogy, Novosibirsk.  
<sup>3</sup> Bioinstitut of the University of Melbourne, Melbourne.
- 12<sup>45</sup> – 13<sup>00</sup> **R.A.Hmelnitsky**, V.A.Dravin, A.A.Tal, M.I.Latushko, A.A.Homich, A.V.Homich, A.S.Trushin, A.A.Alekseev, S.A.Terentyev. Swelling and amorphization of diamond at ion implantation.  
*P.N.Lebedev Physical Institute, RAS, Moscow.*
- 13<sup>00</sup> – 13<sup>30</sup> **Paul F.A.Alkemade**. Sub-Nanometer Focused Helium Ion Beam for Structuring Materials on the Nanoscale (*invited report*)  
*Kavli Institute of Nanoscience, Delft University of Technology, Delft, The Netherlands*

## Lunch (13<sup>30</sup> – 14<sup>30</sup>)

14<sup>30</sup> – 18<sup>30</sup>

**visits to:**

SB RAS Exponential Centre;  
Technopark of the Novosibirsk Akademgorodok;  
Novosibirsk laser on free electrons;  
visiting ISP (ion- and electron-induced nanostructuring, implanters);  
INP (electron, neutron and ion radiation, implanters, accelerators).

19<sup>00</sup> – banquet.

**Friday, 26 October**

**Session 11.**

**Chairman – N.N.Gerasimenko**

- 09<sup>00</sup> – 09<sup>30</sup> **A.A.Ivanov**, A.V.Burdakov, V.I.Davydenko. Ion sources and accelerators for nuclear doping and boron neutron-capture therapy (*invited report*)  
*G.I.Budker Institute of Nuclear Physics, SB RAS, Novosibirsk.*
- 09<sup>30</sup> – 10<sup>00</sup> **K.V.Rudenko**, V.F.Lukichev, A.A.orlikovsky. Plasma-immersed ion implantation and its perspective applications in technologies of nanoelectronics and nanostructures (*invited report*).  
*RAS Physico-Technological Institute (RAS PTI), Moscow.*
- 10<sup>00</sup> – 10<sup>30</sup> A.A.Leino<sup>1</sup>, O.H.Pakarinen<sup>1</sup>, **F.Djurabekova**<sup>1</sup>, K.Nordlund<sup>1</sup>, Mark Ridgway<sup>2</sup>. Mechanism of swift heavy ion beam elongation of embedded nanoclusters (*invited report*)  
<sup>1</sup>University of Helsinki and Helsinki Institute of Physics, Helsinki, Finland  
<sup>2</sup>Department of Electronic Materials Engineering, The Australian National University, Australia
- 10<sup>30</sup> – 10<sup>45</sup> **G.P.Pokhil**, V.V.Cherdyn'tsev. Ion beams control assisted with dielectric channels.  
*D.V.Skobeltsev RINP, MSU, Moscow.*
- 10<sup>45</sup> – 11<sup>00</sup> New trends in ion implantation  
ULVAC/Tokyo Boeki, Russia.

**Coffee break — 15 min.**

11<sup>15</sup> – 11<sup>45</sup> **Yu.P.Sharkeev**<sup>1,2</sup>, **I.A.Kurzina**<sup>2,3</sup>. Nanostructuring titanium and ion implantation **(invited report)**

<sup>1</sup> Institute of Resistance Physics and Material Science, SB RAS, Tomsk.

<sup>2</sup> Tomsk Polytechnical University, Tomsk.

<sup>3</sup> Tomsk State University, Tomsk.

11<sup>45</sup> – 12<sup>00</sup> **A.A.Novoselov**, **V.Ya.Bayankin**, **F.Z.Gilmudinov**. About the manifestation of small-dosage long-distance effect under ion implantation of rolled copper-nickel foils.

*Physico-Technical Institute of UrB RAS, Izhevsk.*

12<sup>00</sup> – 12<sup>15</sup> **M.Yu. Bekhtina**<sup>1</sup>, **A.V.Irzhak**<sup>2</sup>, **V.V.Koledov**<sup>1</sup>. Influence of focused ion beam on surface layers of Ti<sub>2</sub>NiCu ribbon.

<sup>1</sup>V.A.Kotelnikov Institute of Radiotechnics and Electronics, RAS, Moscow.

<sup>2</sup> National Research Technological University «MIS and A», Moscow.

12<sup>15</sup> – 12<sup>30</sup> **A.V.Zhikharev**<sup>1</sup>, **I.N.klimova**<sup>1</sup>, **V.Ya.Bayankin**<sup>1</sup>, **E.V.Kharanzhevsky**<sup>2</sup>. Influence of laser radiation on segregation processes in Cu<sub>50</sub>Ni<sub>50</sub> foils with a sprayed-on Al layer.

<sup>1</sup>Physico-Technical Institute, UrB RAS, Izhevsk.

<sup>2</sup>Udmurt State university, Izhevsk.

12<sup>30</sup> – 12<sup>45</sup> **V.L.Vorobyev**<sup>1</sup>, **P.V.Bykov**<sup>1</sup>, **V.Ya.Bayankin**<sup>1</sup>, **O.A.Bureev**<sup>2</sup>. Change of mechanical properties of carbon steel depending on the impulse chrome ion-induced radiation dosage.

<sup>1</sup>Physico-Technical Institute, UrB RAS, Izhevsk.

<sup>2</sup>Institute of Electrophysics, UrB RAS, Yekaterinburg.

12<sup>45</sup> – 13<sup>00</sup> **G.Abadias**<sup>1</sup>, **V.V.Uglov**<sup>2</sup>, **A.Yu.Rovbut**<sup>2</sup>, **I.A.Solodukhin**<sup>2</sup>, **S.V.Zlotsky**<sup>2</sup>. Structural-phase changes in TiZrAlN cap layers implanted with xenon ions.

<sup>1</sup>Poitiers University, France, Poitiers.

<sup>2</sup>Belarus State University, Minsk.

**Lunch (13<sup>00</sup> – 14<sup>30</sup>)**

## Session13.

## Chairman – A.V. Dvurechenskii

- 14<sup>30</sup> – 15<sup>00</sup> **Julian Duchaine, Frank Torregrosa, Yohann Spiegel.** Challenges and use of plasma immersion ion implantation for advanced semiconductor devices (*invited report*).  
*IBS, Peynier, France.*
- 15<sup>00</sup> – 15<sup>15</sup> **S.P.Kobeleva<sup>1</sup>, I.M.Anfimov<sup>1</sup>, A.M.Musalitin<sup>1</sup>, V.V.Kalinin<sup>2</sup>, K.V.Fritzler<sup>2</sup>.** Influence of technological prehistory on thermoacceptors formation in silicon crucibleless zone melting (CZM) radiated by relativistic electrons  
<sup>1</sup>*National research technological University, Moscow*  
<sup>2</sup>*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk*
- 15<sup>15</sup> – 15<sup>30</sup> **A.A.Korepanov, V.V.Bolotov, K.E.Ivlev, P.M.Korusenko, D.V.Cheredov.** Structural and electrophysical properties of por-Si/SnO<sub>x</sub> nanocomposite obtained with the impact of a powerful nanosecond laser beam.  
*Omsk Affiliated Branch of A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Omsk.*
- 15<sup>30</sup> – 15<sup>45</sup> **A.V.Stepanov, G.M.Filippov.** Simulation of particles channeling in carbon nanotube arrays.  
<sup>1</sup>*I.Ya.Yakovlev Chuvash State Pedagogical University.*  
<sup>2</sup>*Cheboksary Polytechnical Institute (affiliated branch) of the Moscow State Open University, Cheboksary.*
- 15<sup>45</sup> – 16<sup>00</sup> **M.I.Makoviychuk.** Flicker-noise spectroscopy — a perspective analytical investigation method for ion-doped semiconductor layers.  
*Yaroslavl Affiliated Branch of the Physico-Technological Institute, RAS, Yaroslavl.*

16<sup>00</sup>

**CLOSING OF THE CONFERENCE.**

## POSTER PRESENTATIONS

### POSTER SECTION C1

- C1-1. **A.I.Gumarov**<sup>1</sup>, **N.M.Liadvov**<sup>2</sup>, **E.I.Dulov**<sup>1</sup>, **V.F.Valeev**<sup>2</sup>, **N. Dogan**<sup>3</sup>, **B.Z.Rameev**<sup>2,3</sup>, **A. Mackova**<sup>4,5</sup>, **V. Hnutowicz**<sup>5</sup>, **L.R.Tagirov**<sup>1,2</sup>, **R.I.Haibullin**<sup>1,2</sup>. Investigating the effect of substrate temperature on structural and magnetic properties of ZnO, implanted by Fe or Co ions.

<sup>1</sup>Kazan (Privolzhsk) Federal University, Kazan.

<sup>2</sup>Kazan Physico-Technical Institute of the KSC, RAS.

<sup>3</sup>Gebze Institute of Technology, Gebze-Kocaeli, Turkey

<sup>4</sup>Nuclear Physics Institute of the AS CR, Rez 130, Czech Republic

<sup>5</sup>Department of Physics, J.E. Purkinje University, Usti nad Labem, Czech Republic

- C1-2. **G.G.Gumarov**, **A.V.Alekseev**, **V.Yu.Petuhov**, **V.F.Valeev**. Dose dependence of magnetic properties of iron silicides ion-synthesized in external magnetic field.

*E.K.Zavoisky Kazan Physico-Technical Institute of the KAZSC, RAS, Kazan.*

- C1-3. **N.N.Halitov**<sup>1,2</sup>, **M.N.Liadvov**<sup>1</sup>, **V.A.Shustov**<sup>1</sup>, **R.I.Haibullin**<sup>1,2</sup>, **I.A.Faizrakhmanov**<sup>1,2</sup>, **P.A.Gorbatova**<sup>2</sup>, **V.V.Parfenov**<sup>2</sup>. Formation of nanocomposite films of BaTiO<sub>3</sub>:Co multi-ferroics with the ion-stimulated deposition method.

<sup>1</sup> Kazan Physico-Technical Institute, Kazan.

<sup>2</sup> Kazan Federal University, Kazan.

- C1-4. **E.E.Rodiankina**<sup>1</sup>, **S.S.Kosolobov**<sup>1,2</sup>, **A.V.Latyshev**<sup>1,2</sup>. Silicon surface morphology under epitaxial growth and sublimation.

<sup>1</sup>A.V.Rzhanov Institute of Semiconductor Physics, SB RAS., Novosibirsk.

- C1-5. **G.F.Karlova**<sup>1</sup>, **G.I.Koltsov**<sup>2</sup>, **S.Yu.Yurchuk**<sup>2</sup>. Ion implantation of beryllium into gallium arsenide and the possibility of its use in producing heterobipolar transistors.

<sup>1</sup>OJSC «Research institute of Semiconductor Devices», Tomsk.

<sup>2</sup> RTU MIS, Moscow.

- C1-6. **N.N.Gerasimenko**<sup>1</sup>, **N.Medetov**<sup>1</sup>, **Yu.A.Ryabkin**<sup>2</sup>, **S.Zh.Tokmoldin**<sup>2</sup>, **K.B.Tynyshtykbaev**<sup>2</sup>. About the same common origin of radiation and non-radiation cracks with the example of anode-etched p-Si (100).

<sup>1</sup>MIET, Zelenograd.

<sup>2</sup>Physico-Technical Institute MES KR, Almati.

- C1-7. **R.S.Madatov**, **TT.B.Tagiev**, **Yu.M.Mustafaev**, **F.P.Abasov**. Influence of penetrating radiation on photoelectric properties of GaS and GaS:Er monocrystals.

*Institute of Radiation Problems of the Aizerbaidjan NAS, Baku.*

- C1-8. **A.V.Zhelannov<sup>1</sup>**, **V.E.Udaltsov<sup>2</sup>**, **D.G.Fedorov<sup>1,2</sup>**. Use of ion implantation in ohmic contacts formation to diode structures based on gallium nitride  
<sup>1</sup>OJSC «RDB — Planet», Novgorod-the-Great.  
<sup>2</sup>Ya.Mudry Novgorod State University, Novgorod-the-Great (Veliky Novgorod).
- C1-9. **A.K.Shestakov**, **K.S.Zhuravlev**. Computer research of electro-physical processes in ion-doped field GaAs-transistor with Shottky gate at the change of the channel profile doping parameters.  
*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*
- C1-10. **I.I.Izhnin<sup>1</sup>**, **E.I.Fitsych<sup>1</sup>**, **A.Yu.Bonchik<sup>2</sup>**, **G.V.Savitsky<sup>2</sup>**, **A.V.Voitsekhovskiy<sup>3</sup>**, **S.A.Dvoretsky<sup>4</sup>**, **N.N.Mikhailov<sup>4</sup>**, **Yu.G.Sidorov<sup>4</sup>**, **V.S.Varavin<sup>4</sup>**, **K.D.Mynbaev<sup>5</sup>**. Defect structure relaxation of epitaxial CdHgTe films subjected to low- and high-energy ion processing.  
<sup>1</sup>Scientific-production Enterprise "Karat", Lvov, Ukraine.  
<sup>2</sup>Ya.S.Pidsrtrigach Institute of Applied problems of Mechanics and Mathematics, NAS of Ukraine., Lvov.  
<sup>3</sup>Tomsk State University, Tomsk.  
<sup>4</sup>A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.  
<sup>5</sup>A.F.Ioffe Physico-Technical Institute, St.-Petersburg.
- C1-11. **A.V.Voitsekhovskiy<sup>1</sup>**, **N.H.Talipov<sup>2</sup>**. Influence of power IR impulse laser radiation on boron-implanted p-type heteroepitaxial Cd<sub>x</sub>Hg<sub>1-x</sub>Te layers.  
<sup>1</sup>Tomsk State University, Tomsk.  
<sup>2</sup>Peter-the-Great Military Academy of Rocket Strategic Troops, Moscow.
- C1-12. **G.V.Baranov**, **A.G.Italiantsev**, **O.M.Orlov**. Implanted As redistribution under radiation defect-stimulated diffusion.  
*OJSC «RIME, Moscow, Zelenograd.*
- C1-13. **M.V.Dragut<sup>1,2</sup>**, **D.A.Usik<sup>1</sup>**, **D.M.Misharin<sup>1</sup>**. Estimate of depleted surface GaAs region after SCE with the layer-by-layer chemical etching method.  
<sup>1</sup>OJSC «RDB – Planet», Novgorod-the-Great 9Veliky Novgorod.  
<sup>2</sup>Ya.Mudry Novgorod State University, Veliky Novgorod.
- C1-14. **A.A.Koshkarev**, **A.V.Nenashev**, **A.V.Dvurechenskii**. Registration of anisotropy in calculating elastic deformation in quantum wires and dots.  
*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*
- C1-15. **V.V.Karzanov**, **N.A.Karpov**. Effect of silicon implantation on AlN luminescent properties.  
*N.I.Lobachevsky Nizhegorod State University, Nizhny Novgorod.*

- C1-16. **P.A.Kuchinskaya**<sup>1</sup>, V.A.Zynoviyev<sup>1</sup>, A.V.Nenashev<sup>1,2</sup>, V.A.Armbrister<sup>1</sup>, A.V.Dvurechenskiy<sup>1,2</sup>. QDs spatial organization into ring chains in multilayer Ge/Si structures.
- <sup>1</sup>A.V.Rzhanov Institute of Semiconductor pPhysics, SB RAS Novosibirsk.  
<sup>2</sup>Novosibirsk State University, Novosibirsk.
- C1-17. **A.A.Ghismatulin**<sup>1</sup>, A.H.Antonenko<sup>1,2</sup>, G.N.Kamaev<sup>1,2</sup>, G.A.Kachurin<sup>1</sup>, S.G.Cherkova<sup>1,2</sup>, A.G.Cherkov<sup>1,2</sup>, V.A.Skuratov<sup>3</sup>. Electro-physical properties of multilayer Si/SiO<sub>2</sub> structures with Si nanoclusters form with high-energy Xe ion radiation.
- <sup>1</sup> A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.  
<sup>2</sup> Novosibirsk State University, Novosibirsk.  
<sup>3</sup> United Nuclear Research Institute, Dubna.
- C1-18. **F.F.Komarov**<sup>1</sup>, Yu.Zhuk<sup>2</sup>, L.A.Vlasukova<sup>1</sup>, O.V.Milchanin<sup>1</sup>, V.Vesh<sup>3</sup>, E.Vendler<sup>3</sup>, M.V.Greben<sup>1</sup>, M.A.Mokhovikov<sup>1</sup>, I.N.Parkhomenko<sup>1</sup>. Structure and optical properties of silicon layers with InSb and InAs nanocrystals formed by ion-beam synthesis.
- <sup>1</sup> Belarus State University, Minsk, Belarus.  
<sup>2</sup> M. Curie-Skłodowska University, Lublin, Poland  
<sup>3</sup> F. Schiller University Jena, Jena, Germany
- C1-19. **V.A.Lastkin**<sup>2</sup>, A.S.Ionov<sup>2</sup>, V.V.Gavrushko<sup>1</sup>. Research of doping silicon ion-diffusion profiles by arsenic.
- <sup>1</sup>Ya.Mudry Novgorod State University, Novgorod-the-Great (Veliky Novgorod).  
<sup>2</sup>OJSC «RDB - Planet», Novgorod-the-Great (Veliky Novgorod).
- C1-20. **R.I.Batalov**<sup>1</sup>, R.M.Bayazitov<sup>1</sup>, G.A.Novikov<sup>1</sup>, N.V.Kurbatova<sup>1</sup>, P.I.Gaiduk<sup>2</sup>, G.D.Ivlev<sup>2</sup>, S.L.Prokopyev<sup>2</sup>. SiGe/Si heterostructures formation with magnetron spraying methods and nanosecond ion/laser annealing.
- <sup>1</sup>E.K.Zavoisky Kazan Physico-Technical Institute of the KazSC, RAS, Kazan.  
<sup>2</sup>Belarus State University, Minsk, Belarus.
- C1-21. **D.I.Tetelbaum**<sup>1</sup>, A.N.Mikhailov<sup>1</sup>, D.V.Guseinov<sup>1</sup>, A.I.Belov<sup>1</sup>, A.B.Kostiuk<sup>1</sup>, D.S.Korolev<sup>1</sup>, M.P.Fedonin<sup>2</sup>, D.A.Pavlov<sup>2</sup>, A.I.Bobrov<sup>2</sup>, V.N.Trushin<sup>1</sup>, A.S.Markelov<sup>1</sup>. Peculiarities of ion-beam impact on silicon and aluminum oxides layers having Au nanoclusters.
- <sup>1</sup>N.I.Lobachevsky Research Institute of the Nizhegorod State University, Nizhny Novgorod.  
<sup>2</sup> Physical Faculty of N.I.Lobachevsky Nizhegorod State university, Nizhny Novgorod.
- C1-22. **S.N.Nagornykh**<sup>1</sup>, V.I.Pavlenkov<sup>1</sup>, I.A.Chugrov<sup>1</sup>, A.V.Ershov<sup>1</sup>, A.N.Mikhailov<sup>1</sup>, A.I.Belov<sup>1</sup>, **D.I.Tetelbaum**<sup>1</sup>, D.I.Kryzhkov<sup>2</sup>, L.V.Krasilnikova<sup>2</sup>. About the influence of silicon nanocrystals size on the temperature dependence of photoluminescence spectra.
- <sup>1</sup>N.I.Lobachevsky Nizhegorod State University, Nizhny Novgorod.  
<sup>2</sup>Institute of Microstructures Physics, RAS, Nizhny Novgorod.

- C1-23. **A.O.Timofeeva, A.I.Belov, A.N.Mikhailov, D.I.Tetelbaum.** Effect of built-in electric field under ion radiation of silicon for the secondary radiation defects system.  
*Research Physico-Technical Institute of N.I.Lobachevsky Nizhegorod State University, Nizhny Novgorod.*
- C1-24. **A.N.Mikhailov<sup>1</sup>, D.S.Korolev<sup>1</sup>, A.B.Kostiuk<sup>1</sup>, A.I.Belov<sup>1</sup>, D.I.Tetelbaum<sup>1</sup>, D.A.Grachev<sup>2</sup>, I.A.Chugrov<sup>2</sup>, A.V.Ershov<sup>2</sup>.** Influence of radiation with Au, Er and Zr ions on the optical properties of oxide structures with Si nanocrystals  
<sup>1</sup> *Research Physico-Technical Institute of N.I.Lobachevsky NNSU, Nizhny Novgorod.*  
<sup>2</sup> *N.I.Lobachevsky Nizhegorod State University, Nizhny Novgorod.*
- C1-25. **T.H.Hasanov.** Oxygen and water vapor diffusion on the silicon dioxide — silicon interface.  
*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS Novosibirsk.*
- C1-26. **D.I.Rogilo<sup>1,2</sup>, L.I.Fedina<sup>1</sup>, S.S.Kosolobov<sup>1,2</sup>, A.V.Latyshev<sup>1,2</sup>.** A change of kinetic limitations of high-temperature Si growth on Si(111)-(7×7)  
<sup>1</sup> *A.V.Rzhanov Institute of Semiconductor Physics, SB RAS Novosibirsk.*  
<sup>2</sup> *Novosibirsk State University, Novosibirsk.*
- C1-27. **V.N.Popok<sup>1</sup>, J.Samela<sup>2</sup>, K.Nordlund<sup>2</sup>, V.P.Popov<sup>3</sup>.** Radiation Damage in Diamond by Implantation of Argon Cluster Ions  
<sup>1</sup> *Department of Physics and Nanotechnology, Aalborg University, Denmark,*  
<sup>2</sup> *Department of Physics and Helsinki Institute of Physics, University of Helsinki, Finland*  
<sup>3</sup> *Institute of Semiconductor Physics, Novosibirsk*
- C1-28. **I.E.Tyschenko<sup>1</sup>, V.A.Volodin<sup>1,2</sup>, V.P.Popov<sup>1</sup>.** Crystallization of SOI films implanted with big hydrogen ion doses and annealed at the millisecond pulse regime.  
<sup>1</sup> *A.V.Rzhanov Institute of Semiconductor Physics, SB RAS, Novosibirsk.*  
<sup>2</sup> *Novosibirsk State University, Novosibirsk.*
- C1-29. **O.N.Gorshkov, D.A.Pavlov, I.N.Antonov, M.E.Shenina, A.Yu.Dudin, A.I.Bobrov, A.P.Kasatkin, K.V.Sidorenko.** Investigation of gold nanodimensional particles formation process in germanium dioxide thin films by ion implantation method.  
*N.I.Lobachevsky Research Physico-Technical Institute of the Nizhegorod State University, Nizhny Novgorod.*

## POSTER SECTION C2

- C2-1. **N.M.Liadov<sup>1</sup>, Yu.N.Osir<sup>2</sup>, T.S.Kavetsky<sup>3</sup>, A.L.Stepanov<sup>1</sup>.** Synthesis of silver nanoparticles under ion implantation of organically-nonorganic hybrid glass-polymer composites As<sub>2</sub>S<sub>3</sub>-ureasil.  
<sup>1</sup> *E.K.Zavoisky Kazan Physico-Technical institute of RAS, Kazan*  
<sup>2</sup> *Kazan Federal University, Kazan.*  
<sup>3</sup> *Ioan Franko Drogobychsk Pedagogical university, Drogobych, Ukraine.*



- C2-2. **N.M.Liadov**, V.F.Valeev, V.I.Nuzhdin, A.L.Stepanov, I.A.Faizrahmanov. Optical properties research of silver ion-implanted ZnO Al<sub>2</sub>O<sub>3</sub>.  
*E.K.Zavoisky Kazan Physico-Technical Institute of Kaz SC, RAS, Kazan.*
- C2-3. O.N.Gorshkov, D.A.Pavlov, I.N.Antonov, **M.E.Shenina**, A.Yu.Dudin, A.I.Bobrov, A.P.Kasatkin. Peculiarities of metallic nanoparticles formation in ZrO<sub>2</sub>(Y) matrix with the method of ion implantation.  
*N.I.Lobachevsky Nizhegorod State University, Nizhny Novgorod.*
- C2-4. **V.V.Privezentev**<sup>1</sup>, V.S.Kulikauskas<sup>2</sup>, V.V.Zatekin<sup>2</sup>, D.V.Petrov<sup>2</sup>, A.V.Makunin<sup>2</sup>, A.A.Shemukhin<sup>2</sup>, A.V.Putrik<sup>3</sup>. Effect of annealing temperature and atmosphere for nanoparticles formation in silicon by the method of ion doping with zinc.  
<sup>1</sup>RAS Physico-Technological Institute, Moscow.  
<sup>2</sup>D.V.Skobeltsin RINP, M.V.Lomonosov MSU, Moscow.  
<sup>3</sup>B.N.Eltsin Ural Federal State University, Yekaterinburg.
- C2-5. **E.V.Medvedeva**, S.S.Aleksandrova. Quantitative analysis of disoriented nanoblock structure obtained by ion-beam processing.  
*Institute of Electrophysics, UrB of RAS, Yekaterinburg.*
- C2-6. **A.A.Dmitrievsky**<sup>1</sup>, N.Yu.Efremova<sup>1</sup>, A.R.Lovtsov<sup>1</sup>, E.Yu.Isaeva<sup>1</sup>, M.V.Badylevich<sup>2</sup>. Influence of low-intensity beta-radiation on thin films-on-silicon physico-mechanical properties.  
<sup>1</sup>G.R.Derzhavin Tambov State University, Tambov.  
<sup>2</sup>Light and Lighting Laboratory, Catholic University College Gent, Gent, Belgium
- C2-7. **V.L.Levshunova**<sup>1</sup>, G.P.Pokhi<sup>2</sup>, D.I.Tetelbaum<sup>1</sup>, P.N.Chernykh<sup>2</sup>. Fast ion emission from the reverse side of gallium arsenide wafer under front side radiation by 2-MeV helium ions.  
<sup>1</sup>Research Physico-Technical Institute NSSU, Nizhny Novgorod  
<sup>2</sup>RINP of MSU Moscow.
- C2-8. **A.A/Kolotov**, V.Ya.Bayankin, S.G.Bystrov. Mass transfer in metals under pulse ion radiation.  
*Physico-Technical Institute of UrB RAS, Izhevsk.*
- C2-9. **A.Yu.Drozdov**<sup>1</sup>, N.M.Sazonova<sup>1</sup>, V.Ya.Bayankin<sup>1</sup>, I.L.Nagornykh<sup>2</sup>. Molecular-dynamic shock wave simulation in iron-based amorphous alloys.  
<sup>1</sup>Physico-Technical institute of UrB RAS, Izhevsk.  
<sup>2</sup>Institute of Mechanics of UrB RAS, Izhevsk.
- C2-10. **P.V.Bykov**, V.L.Vorobyev, V.Ya.Bayankin. Formation of surface layers composition, change of surface morphology and carbon steel mechanical properties depending on manganese ion energy.  
*Physico-Technical Institute of UrB RAS, Izhevsk.*

- C2-11. **O.V.Obidina**, I.V.Tereshko, V.P.Redko. Long-distance action effect in metals and alloys after radiating them in glow discharge plasma.  
*Belarus-Russian University, Mogilev, Belarus.*
- C2-12. **V.V.Poplavsky**, I.M.Bely, A.V.Dorozhko. Peculiarities of catalitically active layers formation based on glass-carbon using an electric-bow ion source.  
*Belarus State Technological University, Minsk, Belarus.*
- C2-13. **V.A.Fedorov**<sup>1</sup>, Yu.A.Kochergina<sup>1</sup>, L.G.Karyev<sup>2</sup>, A.A.Lobachev<sup>1</sup>. Research of physico-chemical processes and properties of ion crystals under metal implantation in thermoelectric impact conditions.  
<sup>1</sup>G.R.Derzhavin Tambov State University, Tambov.  
<sup>2</sup>Yamalo-Nenetsk Affiliated Branch of the Tyumen State Oil-Gas University, New Urengoi (Novy Urengoi).
- C2-14. **A.A.Ismailov**<sup>1</sup>, N.A.Melnikov<sup>2</sup>. Electro-physical properties of TIS monocrystals.  
<sup>1</sup>Academician G.M.Abdullaev Institute of Physics, NAS of Aizerbaidjan, Baku.  
<sup>2</sup>Aizerbaidjan technixcal University.
- C2-15. **D.S.Petukhov**<sup>1</sup>, T.B.Charikova<sup>1</sup>, O.E.Petukhova<sup>1</sup>, A.A.ivanov<sup>2</sup>. Anisotropy of galvan-magnetic properties in the quasi two-dimensional superconductive compound Nd<sub>2-x</sub>Ce<sub>x</sub>CuO<sub>4+d</sub> with a different level of cerium doping and a different degree of non-stoichiometric disorder.  
<sup>1</sup>Institute of Metal Physics of UrB RAS, Yekaterinburg.  
<sup>2</sup>Moscow Sate Engineering-Physical Institute, Moscow.
- C2-16. **N.S.Filippov**, M.A.Parashchenko, N.V.Vandysheva, O.I.Semenova, S.S.Kosolobov, S.I.Romanov. Developing electrokinetic filters using plasma-stimulated silicon deposition.  
*A.V.Rzhanov Institute of Semiconductor Physics, SB RAS Novosibirsk.*
- C2-17. **D.Melebaev**, **A.M.Tashlieva**. Determining Ga<sub>2</sub>O<sub>3</sub> band gap width with the photoelectric method.  
*Physico-Mathematical Institute of the Academy of Sciencies of Turkmenistan, Ashkhabad.*
- C2-18. **I.G.Pashaev**, I.A.Abuzerov. Effect of different metallic layers microstructure on Shottky diodes electrophysical properties.  
*Baku State University, Baku, Aizerbaidjan*
- C2-19. I.K.Beisembetov, **N.B.Beisenkhanov**, S.K.Zharikov, B.K.Kenzhaliev, K.H.Nusupov, T.K.Ahmetov. Ion synthesis and and properties of silicon carbide films and carbon.  
*Kazakhstan-British Technical University, Almaty*